

Notice of References Cited	Application/Control No. 10/625,878		Applicant(s)/Patent Under Reexamination KEENER, MARK BRADFORD	
	Examiner Tan Dean D. Nguyen		Art Unit 3689	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0198727	12-2002	Ann et al.	705/1
*	B	US-2002/0169658	11-2002	Adler, Richard M.	705/10
	C	US-			
	D	US-			
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	F	US-			
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	I	US-			
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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